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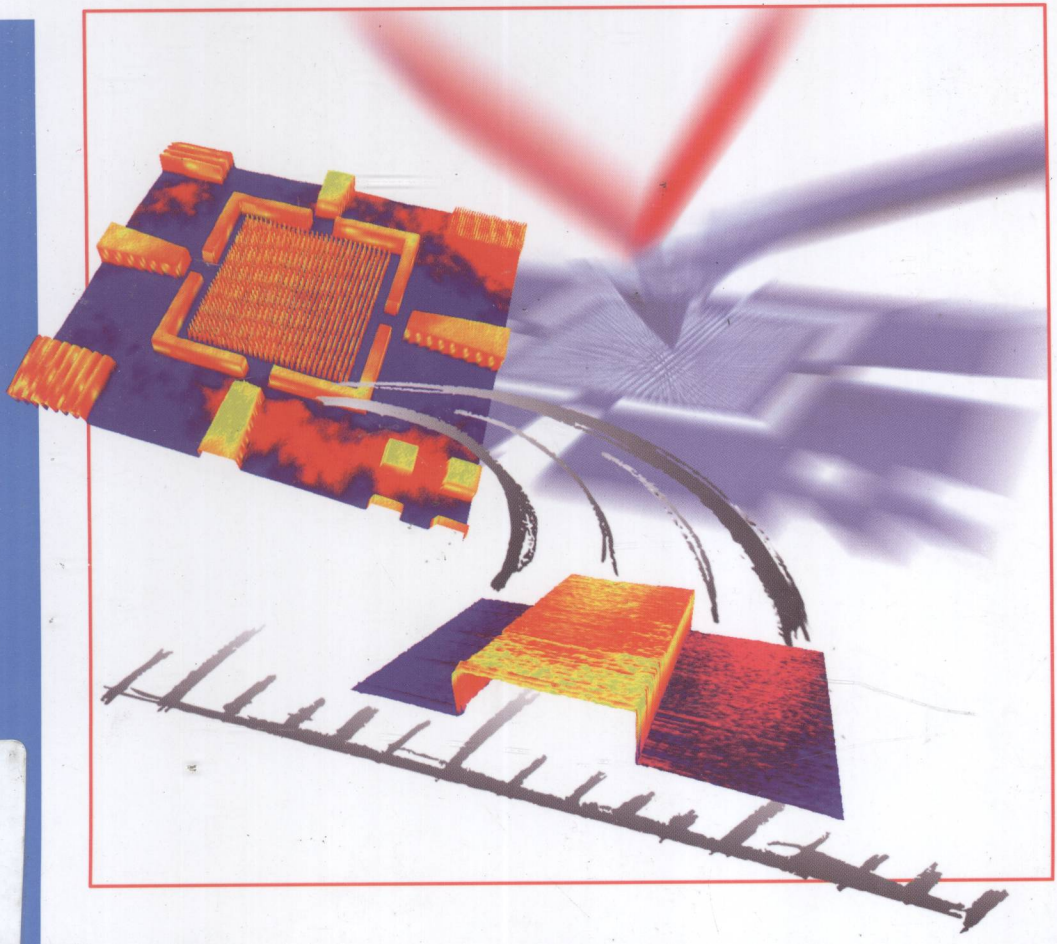
Dimensional and Related Measurements in the Micro- and Nanometer Range



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